

DATA SHEET		Date	29-Jan-05
Model	SUS104805	Temp.	25degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	C.Makino

LINE CONDUCTION

Model Name : SUS104805

Model No. :

Serial No. :

Points : 5

Detector : PEAK/QP/Ave.

Line Mode : VA/VB

Power Supply : DC 48V

Limit1: [EN 55022] Class A(QP)

Limit2: [EN 55022] Class A(Ave.)

Temp. : 25degreeC

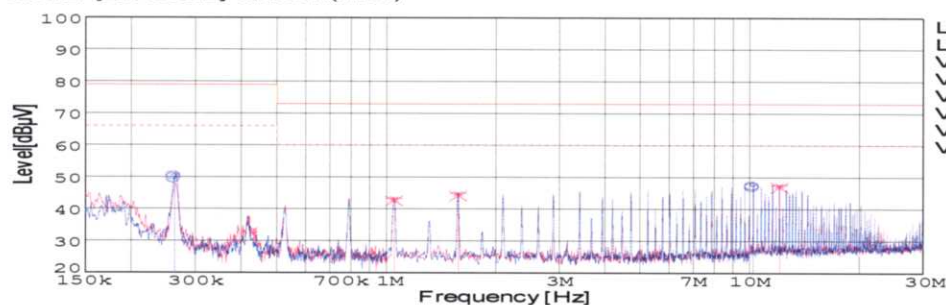
Humi. : 45%

Date : 2005/1/28 15:28

Test Equip. : R3132,ESPC

Load Line : 50mm

Comment : C.Makino



Limit1(QP)
Limit2(Ave.)
VA(PEAK)
VB(PEAK)
VA(QP)
VA(Ave.)
VB(QP)
VB(Ave.)

Vin: DC48V
Iout: 2A

Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.2628	40.6	40	9.8	50.4	49.8	VA	66	79	15.6	29.2
10.2183	37.6	37	10.1	47.7	47.1	VA	60	73	12.3	25.9
1.0475	33.3	32.7	9.9	43.2	42.6	VB	60	73	16.8	30.4
1.5719	35	34.3	9.9	44.9	44.2	VB	60	73	15.1	28.8
12.0514	37.4	36.8	10.1	47.5	46.9	VB	60	73	12.5	26.1

RADIATED EMISSION

Model Name : SUS104805

Model No. :

Serial No. :

Points : 4

Detector : PEAK/QP

Polarization : Hori. & Vert.

Power Supply : DC 48V

Limit: [EN 55022] Class A<3m>

Temp. : 25degreeC

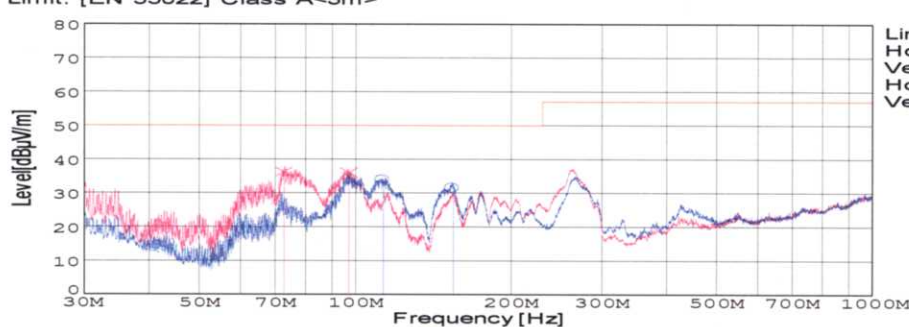
Humi. : 45%

Date : 2005/1/29 11:29

Test Equip. : R3132,ESPC

Load Line : 50mm

Comment : C.Makino



Limit(QP)
Horizontal(PEAK)
Vertical(PEAK)
Horizontal(QP)
Vertical(QP)

Vin: DC48V
Iout: 2A

Frequency [MHz]	Meter Reading (QP) [dBuV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level(QP) [dBuV/m]	Angle [°]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
154.428	52.7	BL	10.3	-31.5	31.5	172	157	Hori.	50	18.5
113.002	55	BL	10.8	-31.7	34.1	0	151	Hori.	50	15.9
72.617	62.4	BL	5.9	-31.9	36.4	77	114	Vert.	50	13.6
96.999	58.5	BL	9.5	-31.8	36.2	264	131	Vert.	50	13.8

COSEL

Conditions

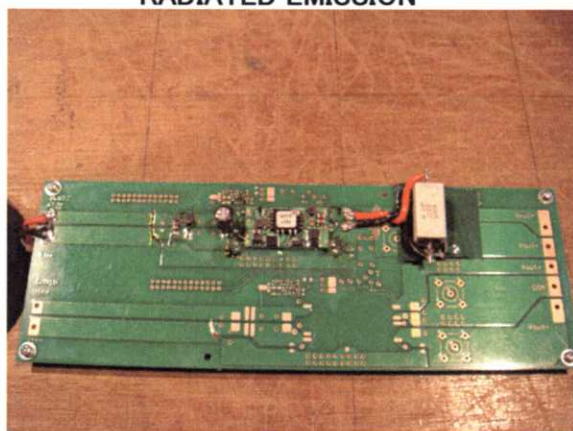
Test : EMI
Model Name : SUS/SUW1048

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

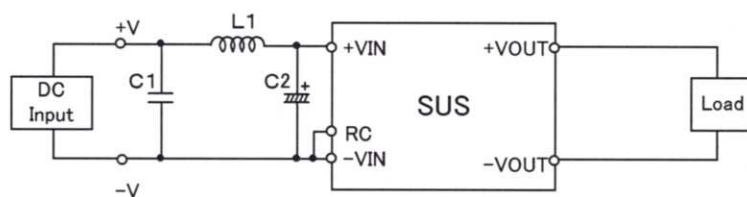


Fig.1 Testing circuitry 1

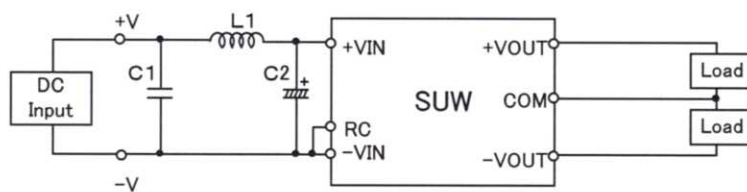


Fig.2 Testing circuitry 2

L1 : 10 μ H	CY3H-100	(KORIN ELECTRONICS)
C1 : 100V 2.2 μ F	C4532JB2A225M	(TDK)
C2 : 100V 47 μ F	UPW2A470M	(NICHICON)